

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	188708	(test or tested or testing) near8 (die or dice or element or component or IC or (integrated near circuit))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 14:05
L2	10204	1 same pad	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 14:05
L3	951	2 same path	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 14:05
L4	716	3 and ((@ad<"20020122") or (@rlad<"20020122"))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 14:11
L5	46	3 same active	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 14:11
L6	641	(testing near4 die) near8 pad	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 14:11
L7	534	6 and ((@ad<"20020122") or (@rlad<"20020122"))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 14:11
L8	4	("5003374"   "5047711"   "5285082"   "5684304").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/08 17:04
L9	22	("5923047").URPN.	USPAT	OR	ON	2006/08/08 17:04